Qualification Test Report

Date: July 1, 2024

Title: Qualification of S25FL128L, 128 Megabit, 3.0-Volt Single Supply Serial Peripheral Interface Flash Non-Volatile Memory with Multi-I/O in WNG008 Packages at ASECL

Reason for choosing the following test vehicles:	**Package BOM**
Scope of qualifications:	**WNG008 package at ASECL**
Assessment of Q-Results:	**Pass**
QTP # :	**202401001**

Stress Test	Abbreviation	Test Condition	Readout	S25FL128L / WNG008 TV 1/2/3 (202401001)	S25FL064L / WSON TV 1 (172402)	S25HS512T / WSON TV 1/2/3 (173011)	S35HS256T / WSON TV 1/2/3 (201211)
				Failed / Stressed	Failed / Stressed	Failed / Stressed	Failed / Stressed
HIGH TEMPERATURE OPERATING LIFE JESD22-A108, JESD85	HTOL	150°C, 3.6V	1000 h	0/90	-	-	-
ESD (CDM) SENSITIVITY JS-002	CM	N/A	750V	0/3	-	-	-
ESD (HBM) SENSITIVITY IEC/EN 61000-4-2, JS-001	ES	100pF, 1500 Ohms	2kV	0/3	-	-	-
STATIC LATCHUP SENSITIVITY JESD78	S_LU	±100 mA	±100 mA	0/3	-	-	-
PRE-CONDITIONING JESD22 -A113	PC	24HRS_125°C 260°C -0 / +5°C MSL3_30°C / 60%RH for 192 hrs	COMP	0/231	0/164	0/885	0/225
TEMP CYCLE JESD22-A104, JESD47	TCT	-65°C to 150°C	500 cy	-	0/82	0/246	0/75
BIASED HAST JESD22-A110	HAST	130°C / 85% RH	96 h	-	0/82	0/161	0/75
UNBIASED HAST TEST JESD22-A118	UHAST	130°C / 85%RH	96 h	-	-	0/231	0/75
HIGH TEMP STORAGE LIFE JESD22-A103	HTSL	150°C	1000 h	-	-	0/55	-
HIGH TEMP STORAGE LIFE JESD22-A103	HTSL	175°C	500 h	-	-	0/50	-

Document History Page

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Rev.	ECN No.	Orig. of Change	Description of Change
**	8047865	BAKC	Initial Release.